ISO 18516:2019 (E)

Surface chemical analysis — Determination of lateral resolution and sharpness in beam based methods with a range from nanometres to micrometres

Contents

Foreword

Introduction

1 Scope

2 Normative references

3 Terms and definitions

4 Symbols and abbreviated terms

5 General information

- 5.1 Background
- 5.2 Survey on principal methods to characterize lateral resolution in imaging surface chemical analysis
- 5.3 Measurement of lateral resolution in imaging surface chemical analysis
- 5.4 Dependence of lateral resolution on scan direction
- 5.5 Reporting results

6 Measurement of lateral resolution using the straight edge method

- 6.1 Introduction
- 6.2 Model functions and sharpness parameters
- 6.3 Requirements for a test sample
- 6.4 Cleaning the straight-edge specimen
- 6.5 Mounting the straight-edge specimen
- 6.6 Operating the instrument
- 6.7 Data acquisition requirements
- 6.8 Determination of D12−88
- 6.9 Determination of line spread function
- 6.10 Reporting

7 Measurement of lateral resolution using the narrow line method

- 7.1 Introduction
- 7.2 Requirements for a test sample
- 7.3 Cleaning the narrow stripe specimen
- 7.4 Mounting the narrow stripe specimen
- 7.5 Operating the instrument
- 7.6 Data acquisition requirements
- 7.7 Determination of wLSF
- 7.8 Reporting

8 Measurement of lateral resolution using the grating method

- 8.1 Introduction
- 8.2 Requirements for a test sample
- 8.3 Cleaning the grating specimen
- 8.4 Mounting the grating specimen
- 8.5 Operating the instrument
- 8.6 Data acquisition
- 8.7 Estimation of effective lateral resolution re by visual inspection of an image or a line scan
- 8.8 Determination of effective lateral resolution re by numerical analysis of a line profile
- 8.8.1 General

8.8.2 Consideration of noise and determination of reduced noise σNr
8.8.3 Determination of dip D
8.8.4 Resolution criterion
8.9 Determination of the effective lateral resolution re using graded gratings
8.9.1 Estimation of effective lateral resolution re by using the resolution criterion in Formula (17)
8.9.2 Determination of effective lateral resolution re by using Formula (17) and an interpolation–extrapolation method
8.10 Reporting

Annex A (informative) The relation between sharpness parameters and effective lateral resolution

Annex B (informative) Straight edge method: systematic underestimation of D12−88 caused by insufficient plateau length Lpl

Annex C (informative) Straight edge method: required length ranges for LESF

Annex D (informative) Straight edge method: the uncertainty of D12−88

Annex E (informative) Narrow stripe method: systematic overestimation of wLSF caused by inappropriately large widths ws of the imaged stripe

Annex F (informative) Narrow line method: the uncertainty of wLSF

Annex G (informative) Imaging of square gratings: reduction of image period for three-stripe gratings

Annex H (informative) Imaging of square gratings: relation between signal-to-noise ratio and effective lateral resolution

Annex I (informative) Imaging of square gratings: minimum number of sampling points per period

Annex J (informative) Imaging of square gratings: uncertainty of re determined by visual inspection of an image or line scan over a series of gratings

Annex K (informative) Imaging of square gratings: Uncertainty of re determined by interpolation–extrapolation

Annex L (informative) Determination of lateral resolution by imaging of square wave gratings — practical example for SIMS

Page count: 53